

FORM PTO-1449  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  LIST OF REFERENCES CITED BY APPLICANT  (Use several sheets if necessary)	ATTY. DOCKET NO. <b>71247-0063</b>	SERIAL NO. <b>10/589,489</b>
	APPLICANT <b>Oussama Laouamri</b>	
	FILING DATE <b>06/25/2007</b>	GROUP ART UNIT <b>Not yet assigned</b>

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
	<b>1.</b>	<b>2003/0120986</b>	<b>06/26/2003</b>	<b>Whetsel</b>			

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	<u>TRANSLATION</u> YES NO PART.		

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	<b>2.</b>	<b>O. Laouamri et al., "Enhancing Testability of System on Chips Using Network Management Protocols", Proceedings of the Design, Automation and Test in Europe Conference and Exhibition (2004)</b>
	<b>3.</b>	<b>O. Laouamri et al., "Hardware-based Network Management Framework for Monitoring and Testing of System-On-Chips", 8th International Conference on Telecommunications, June 15-17, 2005</b>
	<b>4.</b>	<b>O. Laouamri et al., "Remote Testing and Diagnosis of System-on-Chips Using Network Management Frameworks", © 2007, EDAA</b>
	<b>5.</b>	<b>O. Laouamri et al., "Towards a Complete SNMP-Based Supervision of System-on-Chips", Journal of Network and Systems Management, Vol. 13, No. 4, Dec. 2005, pgs. 373-386</b>
EXAMINER  /David Ton/		DATE CONSIDERED  08/01/2009
<p><b>*EXAMINER:</b> Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>		

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /D.T./